

### **Automated design error debug using high-level decision diagrams and mutation operators**

**Raik, Jaan; Repinski, Urmaz; Tšepurov, Anton; Hantson, Hanno; Ubar, Raimund-Johannes; Jenihhin, Maksim**

Microprocessors and microsystems 2013 / p. 505-513 : ill

### **An automated method for mining high-quality assertion sets**

**Heidari Iman, Mohammad Reza; Raik, Jaan; Jenihhin, Maksim; Jervan, Gert; Ghasempouri, Tara** Microprocessors and microsystems 2023 / art. 104773 <https://doi.org/10.1016/j.micpro.2023.104773> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

### **Calculation of probabilistic testability measures for digital circuits with Structurally Synthesized BDDs**

**Jürimägi, Lembit; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan** Microprocessors and microsystems 2020 / art. 103117, 12 p <https://doi.org/10.1016/j.micpro.2020.103117> [Journal metrics at Scopus](#) [Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)

### **Design and verification of Cyber-Physical Systems using TrueTime, evolutionary optimization and UPPAAL**

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### **Design of Cyber Bio-analytical Physical Systems : formal methods, architectures, and multi-system interaction strategies**

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### **Embedded fault diagnosis in digital systems with BIST**

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### **Functional self-test of high-performance pipe-lined signal processing architectures**

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### **Modeling and simulation of circuits with shared structurally synthesized BDDs**

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### **Transition delay fault simulation with parallel critical path back-tracing and 7-valued algebra**

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### **Understanding multidimensional verification : where functional meets non-functional**

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